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<b>Attorney's Docket No.</b>  VAN HARN	<b>Applicant</b>  EMIEL VAN HARN	<b>Appl. No.</b>  10/524,712
<b>Filing Date</b>	<b>Group</b>	<b>Examiner</b>

**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date, if appropriate

**FOREIGN PATENT DOCUMENTS**

Document Number	Date	Country	Class	Subclass	Translation

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

MCB	F.L. Greitzer et al.: "Development of a Framework for Predicting Life of Mechanical Systems: Life Extension Analysis and Prognostics (LEAP)" International Society of Logistics 1999 Symposium, August 30, 1999 – 2 September 1999, pages 1-7, XP002226152, Las Vegas, Nevada, USA
	Nazzari D et al.: "Evaluation of the effectiveness of group screening methods as compared to no group screening", Simulation Conference, 2000. Proceedings. Winter Orlando, FL, USA, 10-13 Dec. 2000, Piscataway, NJ, USA, IEEE, US, December 10, 2000, pages 1499-1504, XP010529703 ISBN: 0-7803-6579-8
	"Reliability Prediction of Board-Mounted Power Modules", Tyco/Electronics Technical Note, 'Online! July 1997, pages 1-6, XP002226153, Retrieved from the Internet: <URL:http://power.tycoelectronics.com>
✓	Luke S R et al.: "Time meter estimation technique for naval equipment", Reliability and Maintainability Symposium, 1993. Proceedings., Annual Atlanta, GA, USA 26-28 Jan. 1993, New York, NY, USA, IEEE, US, 26 January 1993, pages 10-15, XP010110204, ISBN: 0-7803-0943-X

Examiner:

*Mary Catherine Baran*

Date considered:

*6/24/06*

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MCB		Mettas A et al.: "System reliability analysis: the advantages of using analytical methods to analyze non-repairable systems", 2001 Proceedings of the Annual Reliability and Maintainability Symposium. The International Symposium on Product Quality and Integrity. Rams. Philadelphia, PA, Jan. 22-25, 2001, Annual Reliability and Maintainability Symposium, New York, NY: IEEE, 22 January 2001, pages 80-85, XP010531040, ISBN: 0-7803-6615-8
		Mettas A: "Reliability allocation and optimization for complex systems" Reliability and Maintainability Symposium, 2000. Annual Los Angeles, CA, USA 24-27 Jan. 2000, Piscataway, NJ, USA, IEEE, US, 24 January 2000, pages 216-221, XP010367871, ISBN: 0-7803-5848-1
		Mettas A et al.: "Modeling & Analysis for Multiple Stress-Type Accelerated Life Data", 2002 Proceedings of the Annual Reliability and Maintainability Symposium. The International Symposium on Product Quality and Integrity. Rams. Seattle, WA, Jan. 28-31, 2002, Annual Reliability and Maintainability Symposium, New York, NY: IEEE, US, 28 January 2002, pages 343-348, XP010575849 ISBN: 0-7803-7348-0
✓		Y. Z. Friedman: "Advanced Control of Ethylene Plants - What works, What doesn't and Why", Hydrocarbon Asia July/August 1999, pages 1-14, XP002247259

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